# DUAL CHANNEL, HIGH CMR, VERY HIGH SPEED OPTICALLY COUPLED ISOLATOR LOGIC GATE OUTPUT



## APPROVALS

UL recognised, File No. E91231

#### DESCRIPTION

The ICPL2630 / ICPL2631 are dual channel optocouplers consisting of GaAsP light emitting diodes and high gain integrated photo detectors to provide 3500Volts <sub>RMS</sub> electrical isolation between input and output. The output of the detector I.C.'s are open collector Schottky clamped transistors. The ICPL2631 has an internal shield which provides a guaranteed common mode transient immunity specification of 1000V/ $\mu$ s minimum. This unique design provides maximum ac and dc circuit isolation while achieving TTL compatibility. The coupled parameters are guaranteed over the temperature range of 0°C to 70°C, such that a maximum input signal of 5mA will provide a minimum output sink current of 13mA(equivalent to fan-out of eight gates)

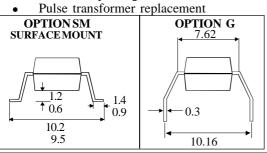
#### **FEATURES**

- High speed 10MBit/s
- High Common Mode Transient Immunity 10kV/µs typical
- Logic gate output
- ICPL2631 has improved noise shield for superior common mode rejection
- Options :-10mm lead spread - add G after part no. Surface mount - add SM after part no. Tape&reel - add SMT&R after part no.

#### APPLICATIONS

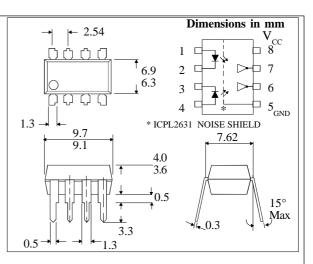
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- Line receiver, data transmission
- Computer-peripheral interface
- Data multiplexing



#### ISOCOM COMPONENTS LTD

Unit 25B, Park View Road West, Park View Industrial Estate, Brenda Road Hartlepool, Cleveland, TS25 1YD Tel: (01429) 863609 Fax :(01429) 863581



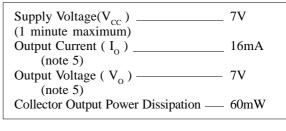
# ABSOLUTE MAXIMUM RATINGS (25°C unless otherwise specified)

Storage Temperature	$-55^{\circ}$ C to $+ 125^{\circ}$ C
Operating Temperature	$0^{\circ}$ C to + $70^{\circ}$ C
Lead Soldering Temperature	
(1/16  inch  (1.6 mm)  from case f)	for 10 secs) 260°C

#### **INPUT DIODE**

Average Forward Current	15mA
(note 5)	
Peak Forward Current	30mA
(less than 1msec duration)(note 5)	
Reverse Voltage	5V
(note 5)	

#### DETECTOR



#### ISOCOM INC

1024 S. Greenville Ave, Suite 240, Allen, TX 75002 USA Tel: (214) 495-0755 Fax: (214) 495-0901 e-mail info@isocom.com http://www.isocom.com

DB92601-AAS/A1

PARAMETER	SYM	DEVICE	MIN	TYP*	MAX	UNITS	TEST CONDITION
High Level Output Current (note 5)	I <sub>oh</sub>			2	250	μΑ	$V_{cc} = 5.5V, V_{o} = 5.5V$ $I_{F} = 250\mu A$
Low Level Output Voltage (note 5)	V <sub>ol</sub>			0.4	0.6	V	$V_{\rm CC} = 5.5$ V, $I_{\rm F} = 5$ mA $I_{\rm OL}$ (sinking) = 13mA
High Level Supply Current (both channels)	I <sub>CCH</sub>			14	30	mA	$V_{\rm CC} = 5.5 V, I_{\rm F} = 0 {\rm mA}$
Low Level Supply Current (both channels)	I <sub>CCL</sub>			26	36	mA	$V_{\rm CC} = 5.5 V, I_{\rm F} = 10 {\rm mA}$
Input Forward Voltage	V <sub>F</sub>			1.55	1.75	V	$I_{F} = 10mA, T_{A} = 25^{\circ}C$
Input Reverse Breakdown Voltage	V <sub>BR</sub>		5			V	$I_{R} = 10\mu A, T_{A} = 25^{\circ}C$
Input Capacitance	C <sub>IN</sub>			60		pF	$V_F = 0$ , $f = 1MHz$
Temperature Coefficient of Forward Voltage	$\frac{\Delta V_{_{\rm F}}}{\Delta T_{_{\rm A}}}$			-1.4		mV/°C	$I_F = 10mA$
Input-output Isolation Voltage (note 4)	V <sub>ISO</sub>		2500	5000		V <sub>RMS</sub>	R.H.equal to or less than 50%, $t = 1$ min. $T_A = 25^{\circ}$ C
Input-output Insulation Leakage Current (note 4)	I <sub>I-O</sub>				1	μΑ	R.H = 45% t = 5s, T <sub>A</sub> = 25°C V <sub>I-0</sub> = 3000V dc
Resistance (Input to Output) (note 4)	R <sub>I-O</sub>			1012		Ω	$V_{I-0} = 500V dc$
Capacitance (Input to Output) (note 4)	C <sub>I-O</sub>			0.6		pF	f = 1MHz
Input-input Insulation Leakage Current (note 6)	I			0.005		μΑ	R.H = 45% t = 5s, T <sub>A</sub> = 25°C $V_{I-0} = 500V dc$
Resistance (Input to input) (note 6)	R <sub>I-I</sub>			1011		Ω	$V_{I-0} = 500V  dc$
Capacitance (Input to input) (note 6)	C <sub>I-I</sub>			0.6		pF	f = 1MHz

# ELECTRICAL CHARACTERISTICS ( $T_{\rm A}{=}~0^{\circ}{\rm C}$ to $70^{\circ}{\rm C}$ Unless otherwise noted )

\* All typicals at  $T_A = 25^{\circ}C$ 

# **RECOMMMENDED OPERATING CONDITIONS**

PARAMETER	SYMBOL	MIN	MAX	UNITS
Input Current, Low Level	I <sub>FL</sub>	0	250	μA
Input Current, High Level	I <sub>FH</sub>	6.3*	15	mA
Supply Voltage, Output	V <sub>cc</sub>	4.5	5.5	v
Fan Out ( TTL Load )	Ν		8	
Operating Temperature	T <sub>A</sub>	0	70	°C

\*6.3mA is a guard banded value which allows for at least 20% CTR degradation. Initial input current threshold value is 5.0mA or less

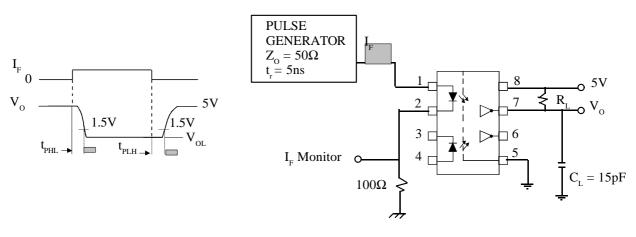
PARAMETER	SYM	DEVICE	MIN	ТҮР	MAX	UNITS	TEST CONDITION
Propagation Delay Time to Logic Low at Output (fig 1)(note2)	t <sub>PHL</sub>			55	75	ns	$R_{L} = 350\Omega, C_{L} = 15pF$
Propagation Delay Time to Logic High at Output ( fig 1 )( note3 )	t <sub>PLH</sub>			45	75	ns	$R_{L} = 350\Omega, C_{L} = 15pF$
Common Mode Transient Immunity at Logic High Level Output (fig 2)(note7)	CM <sub>H</sub>	ICPL2630 ICPL2631	1000	10000 10000		V/µs V/µs	$\begin{split} \mathbf{I}_{\mathrm{F}} &= 0\mathrm{mA}, \ \mathbf{V}_{\mathrm{CM}} &= 50 \mathbf{V}_{\mathrm{pp}} \\ \mathbf{R}_{\mathrm{L}} &= 350 \mathbf{\Omega}, \ \mathbf{V}_{\mathrm{OH}} &= 2 \mathrm{Vmin}. \end{split}$
Common Mode Transient Immunity at Logic Low Level Output (fig 2)(note8)	CML	ICPL2630 ICPL2631	-1000	-10000 -10000		V/µs V/µs	$V_{CM} = 50V_{PP}$ $R_{L} = 350\Omega, V_{OL} = 0.8V max.$

## SWITCHING SPECIFICATIONS AT $T_A = 25^{\circ}C$ ( $V_{CC} = 5V$ , $I_F = 7.5mA$ Unless otherwise noted)

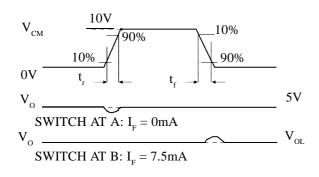
NOTES:-

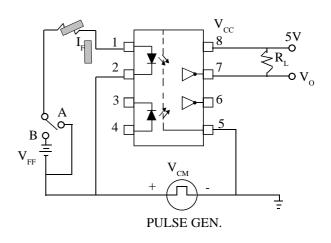
- 1 Bypassing of the power supply line is required, with a 0.01µF ceramic disc capacitor adjacent to each isolator. The power supply bus for the isolator(s) should be seperate from the bus for any active loads. Otherwise a larger value of bypass capacitor (up to 0.1µF) may be needed to supress regenerative feedback via the power supply.
- 2 The t<sub>PHL</sub> propagation delay is measured from the 3.75 mA level Low to High transition of the input current pulse to the 1.5V level on the High to Low transition of the output voltage pulse.
- 3 The  $t_{pLH}$  propagation delay is measured from the 3.75mA level High to Low transition of the input current pulse to the 1.5V level on the Low to High transition of the output voltage pulse.
- 4 Device considered a two terminal device; pins 1, 2, 3, and 4 shorted together, and pins 5, 6, 7 and 8 shorted together.
- 5 Each channel.
- 6 Measured between pins 1 and 2 shorted together and pins 3 and 4 shorted together.
- 7  $CM_{H}$  is the maximum tolerable rate of rise of the common mode voltage to assure that the output will remain in a high logic state (ie Vout > 2.0V).
- 8  $CM_L$  is the maximum tolerable rate of fall of the common mode voltage to assure that the output will remain in a low logic state (ie Vout < 0.8V)

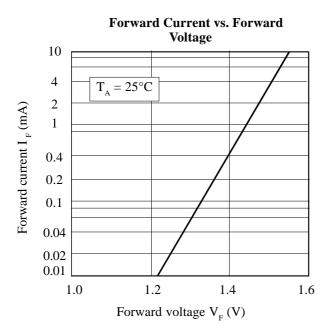
## FIG.1 SWITCHING TEST CIRCUIT

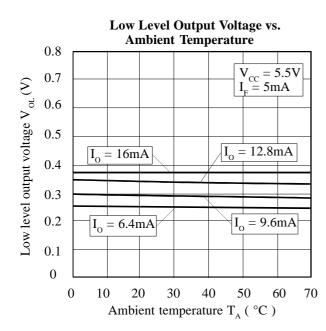


## FIG. 2 TEST CIRCUIT FOR TRANSIENT IMMUNITY AND TYPICAL WAVEFORMS

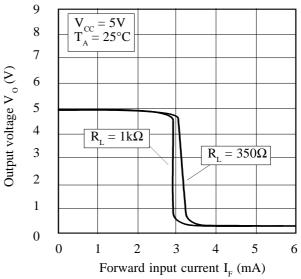








Output Voltage vs. Forward Input Current



High Level Output Current vs. Ambient Temperature

